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Software Analysis, Quality, and Security

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Deadline for manuscript submissions:

closed (15 June 2025)

Message from the Guest Editors

Dear Colleagues,

The rapid progress of digital transformation, accelerated even further by the COVID-19 pandemic, has led to new corporate innovations, significant changes in industries, and even digitalization of our daily lives. As software is at the center of such changes, and its importance and share in industry and society are ever increasing, it is becoming vital to ensure the quality of software to secure core software technologies. Without proper management of quality, software can often cause problems directly related to safety and security as seen from various software defect cases and security incidents which are commonly encountered. In addition, software quality management is essential to reduce the cost of producing, operating, and maintaining software-based products and services as well as to increase productivity and reduce time-to-market. Therefore, software needs to be well developed, thoroughly analyzed, and continuously maintained to ensure its adequate quality.

This SI invites experts to present innovative and significant research achievements in the fields of software development, analysis, and maintenance.











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Message from the Editor-in-Chief

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